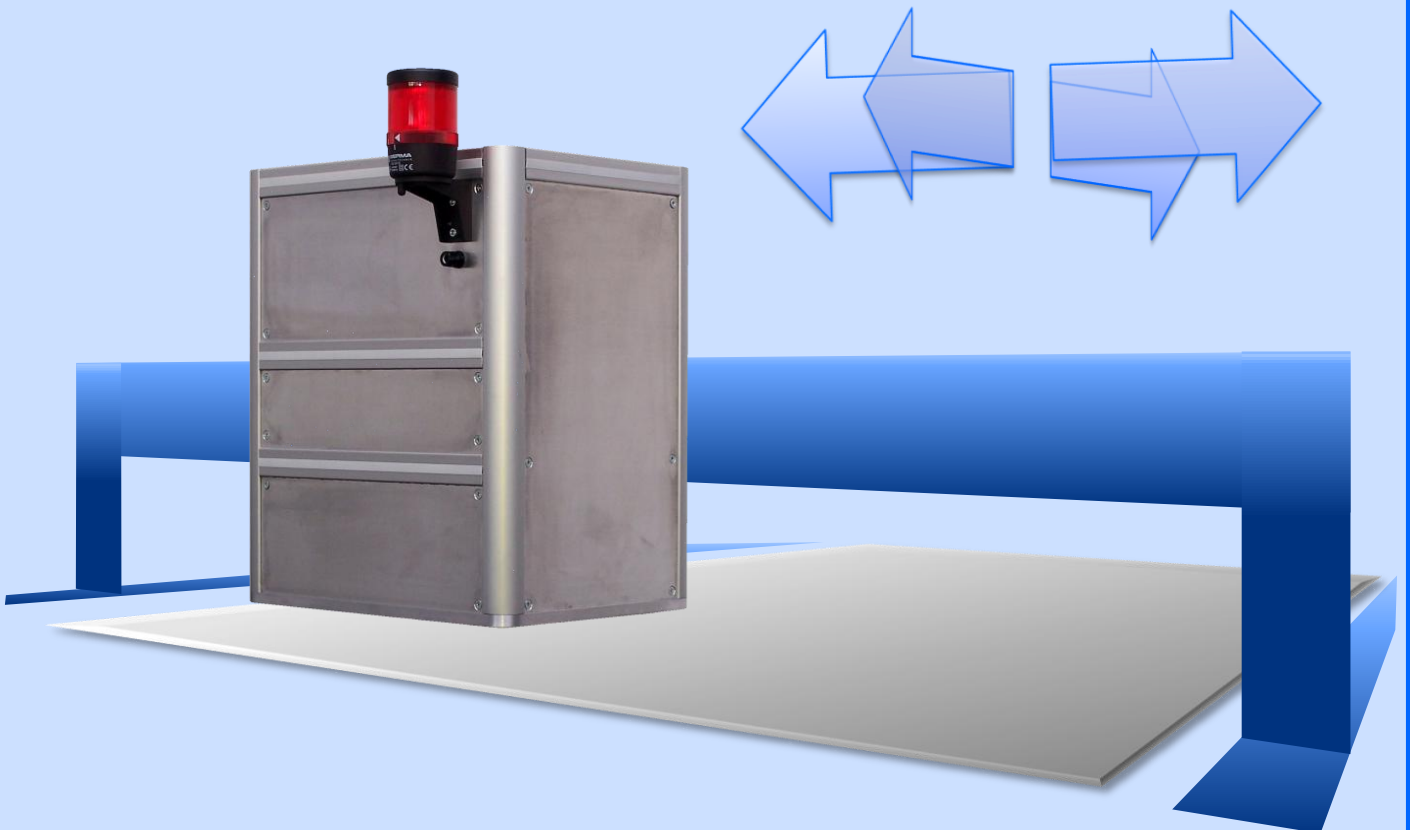
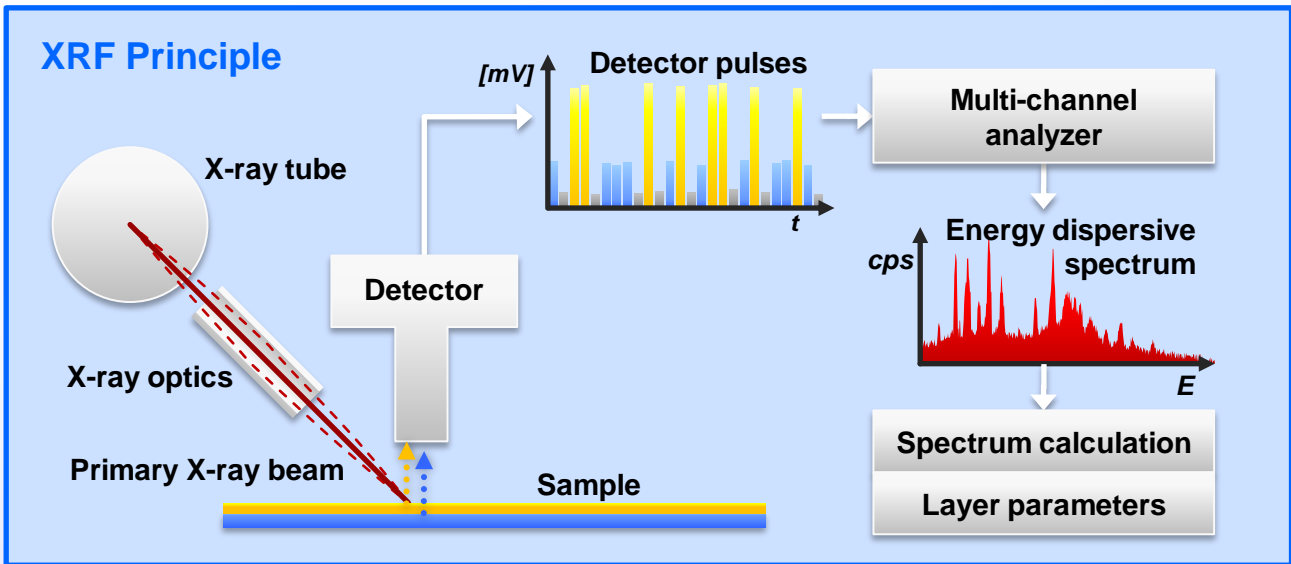


## **XRF-Analysis** **on wide area substrate**

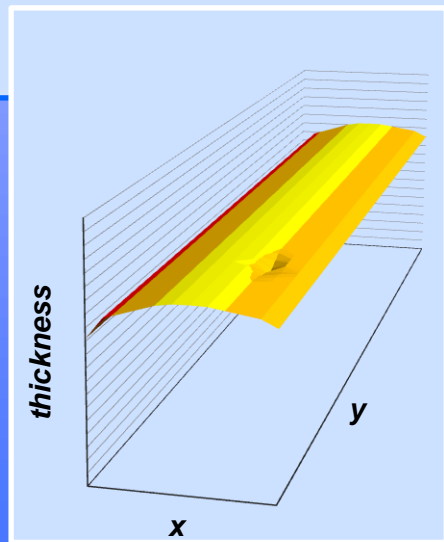
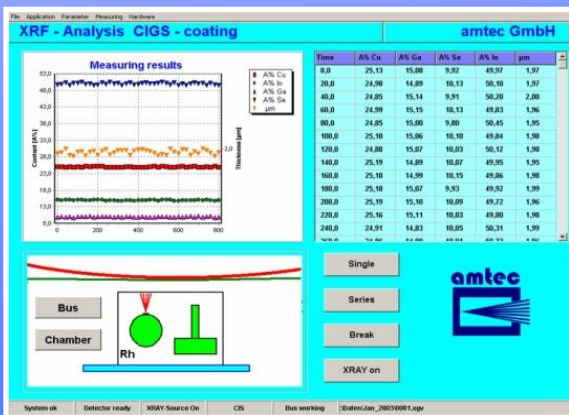
- **Measuring of multi-layers, alloy-layers**
- **Thickness: nm ...  $\mu\text{m}$  / element content ppm ... %**
- **Test item dimensions: up to 1.500 mm x 2.500 mm**
- **Interface to process control system or QM system**
- **Full integration into coating lines (bypass)**
- **Measuring method corresponding ISO 3497 / DIN 50987**

### **Wide area** **XRF-analysis**





- ✓ Analysis of multi-layers, alloy-layers, nanometer light metal coatings too
- ✓ Field of application: solar cells, fuel cells, magnetic layers, barrier layers, ...
- ✓ Measuring period: 5 s ...
- ✓ Reproducibility: 1 %
- ✓ Operational uptime: > 97 %
- ✓ Interface to quality control system
- ✓ Easy-to-use ergonomic human-machine interface
- ✓ Visualization of measurement data with various parameters
- ✓ High operational reliability by internal status control
- ✓ X-ray source with optimized quantum efficiency
- ✓ Maintenance-free Peltier-cooled detector
- ✓ Fully radiation protected in conformity with German regulation for using X-ray
- ✓ Full integration into transportation process
- ✓ Measurable area: up to 1.500 mm x 2.500 mm



Interested? → Feel free to contact us!

amtec Analysenmesstechnik GmbH

Braunstrasse 23-25  
D-04347 Leipzig

Phone +49-(0)341-230 27 60  
Fax +49-(0)341-230 27 70

The manufacturer reserves the right to make changes without notice.

info@amtec-spectro.de  
www.amtec-spectro.de